

Search Notes**Application/Control No.**

10/587,142

Examiner

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**Applicant(s)/Patent under
Reexamination**

LONN, MARKUS

Art Unit

2193

SEARCHED

Class	Subclass	Date	Examiner
708	400-409	8/19/2009	MAI

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor(s) search Double Patent Check Data Bases Search (see search history printout(s))	8/19/2009	MAI